

Docket No. 285545US2X PCT

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Charles S. J. PICKLES, et al.

SERIAL NO: New U.S. PCT Application Based on PCT/IB04/02404

GAU:

FILED: Herewith

EXAMINER:

FOR: DIAMOND MICROELECTRODES

## INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS  
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

## REFERENCES

The applicant(s) wish to make of record the references cited in the International Search Report and listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.

A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

## RELATED CASES

Attached is a list of applicant's pending application(s), published application(s) or issued patent(s) which may be related to the present application. In accordance with the waiver of 37 CFR 1.98 dated September 21, 2004, copies of the cited pending applications are not provided. Cited published and/or issued patents, if any, are listed on the attached PTO form 1449.

A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

## CERTIFICATION

Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.

No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

## DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 285545US2X PCT		SERIAL NO. New U.S. PCT Application Based on PCT/IB04/02404	
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT		Charles S. J. PICKLES, et al.			
		FILING DATE Herewith		GROUP			
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	5 089 802	02/18/92	YAMAZAKI, Shunpei			
	AB	5 844 252	12/01/98	SHIOMI, Hiromu et al.			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
	AO	1 156 136	11/21/01	EP	YES	NO	
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AW	MADORE C., et al., "Detection of Trace Silver and Copper at an Array of Boron-Doped Diamond Microdisk Electrodes", Proceedings of the Symposium on Microfabricated Systems and MEMS, Vol. 2000-19, Pages 159-168, 2000.					
	AX	FUJISHIMA Akira et al., "New Directions in Structuring and Electrochemical Applications of Boron-Doped Diamond Thin Films", Diamond and Related Materials, Vol. 10, No. 9-10, Pages 1799-1803, 2001.					
	AY	SOH K. L. et al., "CVD Diamond Anisotropic Film As Electrode For Electrochemical Sensing", Sensors and Actuators B, Vol. 91, No. 1-3, Pages 39-45, 2003.					
	AZ				<input type="checkbox"/> Additional References sheet(s) attached		
Examiner				Date Considered			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							